# INTEGRATED CIRCUITS



Product specification Supersedes data of 1996 Feb 08 IC23 Data Handbook

1998 Feb 19



74LVT374

#### FEATURES

- Inputs and outputs on opposite side of package allow easy interface to microprocessors
- 3-State outputs for bus interfacing
- Common output enable
- TTL input and output switching levels
- Input and output interface capability to systems at 5V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion/extraction permitted
- No bus current loading when output is tied to 5V bus
- Power-up 3-State
- Power-up reset
- Latch-up protection exceeds 500mA per JEDEC Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model

#### QUICK REFERENCE DATA

#### DESCRIPTION

The 74LVT374 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74LVT374 is an 8-bit, edge triggered register coupled to eight 3-State output buffers. The two sections of the device are controlled independently by the clock (CP) and Output Enable ( $\overline{OE}$ ) control gates.

The register is fully edge triggered. The state of each D input, one set-up time before the Low-to-High clock transition, is transferred to the corresponding flip-flop's Q output.

The 3-State output buffers are designed to drive heavily loaded 3-State buses, MOS memories, or MOS microprocessors. The active-Low Output Enable ( $\overline{\text{OE}}$ ) controls all eight 3-State buffers independent of the clock operation.

When  $\overline{\text{OE}}$  is Low, the stored data appears at the outputs. When  $\overline{\text{OE}}$  is High, the outputs are in the High-impedance "OFF" state, which means they will neither drive nor load the bus.

SYMBOL	PARAMETER	CONDITIONS T <sub>amb</sub> = 25°C; GND = 0V	TYPICAL	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay CP to Qn	C <sub>L</sub> = 50pF; V <sub>CC</sub> = 3.3V	3.2 3.5	ns
C <sub>IN</sub>	Input capacitance	$V_{I} = 0V \text{ or } 3.0V$	4	pF
C <sub>OUT</sub>	Output capacitance	Outputs disabled; V <sub>I/O</sub> = 0V or 3.0V	7	pF
I <sub>CCZ</sub>	Total supply current	Outputs disabled; $V_{CC} = 3.6V$	0.13	mA

#### ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
20-Pin Plastic SOL	–40°C to +85°C	74LVT374 D	74LVT374 D	SOT163-1
20-Pin Plastic SSOP Type II	–40°C to +85°C	74LVT374 DB	74LVT374 DB	SOT339-1
20-Pin Plastic TSSOP Type I	−40°C to +85°C	74LVT374 PW	74LVT374PW DH	SOT360-1

#### **PIN CONFIGURATION**



#### PIN DESCRIPTION

PIN NUMBER	SYMBOL	FUNCTION
1	ŌĒ	Output enable input (active-Low)
3, 4, 7, 8, 13, 14, 17, 18	D0-D7	Data inputs
2, 5, 6, 9, 12, 15, 16, 19	Q0-Q7	Data outputs
11	СР	Clock pulse input (active rising edge)
10	GND	Ground (0V)
20	V <sub>CC</sub>	Positive supply voltage

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### LOGIC SYMBOL



## LOGIC SYMBOL (IEEE/IEC)



#### **FUNCTION TABLE**

	INPUTS		INTERNAL	OUTPUTS		
OE	СР	Dn	REGISTER Q0 – Q7		OFERATING MODE	
L	$\uparrow$	I	L	L	Lood and road register	
L	$\uparrow$	h	Н	Н	Load and read register	
L	\$	Х	NC	NC	Hold	
Н	Х	Х	NC	Z	Disable outputs	

H = High voltage level

High voltage level one set-up time prior to the Low-to-High clock transition h =

Low voltage level L =

L = Low voltage level one set-up time prior to the Low-to-High clock transition

NC= No change

Х = Don't care

High impedance "off" state Z ↑ ↓ =

=

Low-to-High clock transition not a Low-to-High clock transition =

## LOGIC DIAGRAM



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### ABSOLUTE MAXIMUM RATINGS<sup>1, 2</sup>

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V <sub>CC</sub>	DC supply voltage		-0.5 to +4.6	V
I <sub>IK</sub>	DC input diode current	V <sub>I</sub> < 0	-50	mA
VI	DC input voltage <sup>3</sup>		-0.5 to +7.0	V
I <sub>OK</sub>	DC output diode current	V <sub>O</sub> < 0	-50	mA
V <sub>OUT</sub>	DC output voltage <sup>3</sup>	Output in Off or High state	-0.5 to +7.0	V
		Output in Low state	128	
lout	DC output current	Output in High state	-64	mA
T <sub>stg</sub>	Storage temperature range		-65 to 150	°C

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

 The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIM	UNIT	
STWBOL	PARAMEIER	MIN	MAX	UNIT
V <sub>CC</sub>	DC supply voltage	2.7	3.6	V
VI	Input voltage	0	5.5	V
V <sub>IH</sub>	High-level input voltage	2.0		V
V <sub>IL</sub>	Input voltage		0.8	V
I <sub>ОН</sub>	High-level output current		-32	mA
	Low-level output current		32	
I <sub>OL</sub>	Low-level output current; current duty cycle $\leq$ 50%, f $\geq$ 1kHz		64	mA
Δt/Δv	Input transition rise or fall rate; outputs enabled		10	ns/V
T <sub>amb</sub>	Operating free-air temperature range	-40	+85	°C

#### Product specification

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### DC ELECTRICAL CHARACTERISTICS

					LIMITS			
SYMBOL	PARAMETER	TEST CONDITIONS		Temp = -40°C to +85°C			UNIT	
				MIN	TYP <sup>1</sup>	MAX		
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = 2.7V; I <sub>IK</sub> = -18mA			-0.9	-1.2	V	
		V <sub>CC</sub> = 2.7 to 3.6V; I <sub>OH</sub> = -100μA		V <sub>CC</sub> -0.2	V <sub>CC</sub> -0.1			
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = 2.7V; I <sub>OH</sub> = -8mA		2.4	2.5		V	
		V <sub>CC</sub> = 3.0V; I <sub>OH</sub> = -32mA		2.0	2.2		1	
		V <sub>CC</sub> = 2.7V; I <sub>OL</sub> = 100μA			0.1	0.2		
		V <sub>CC</sub> = 2.7V; I <sub>OL</sub> = 24mA			0.3	0.5	1	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 16mA			0.25	0.4	v	
		V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 32mA			0.3	0.5	1	
		V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 64mA			0.4	0.55		
V <sub>RST</sub>	Power-up output low voltage <sup>5</sup>	$V_{CC}$ = 3.6V; I <sub>O</sub> = 1mA; V <sub>I</sub> = GND or V <sub>CC</sub>			0.13	0.55	V	
		V <sub>CC</sub> = 0 or 3.6V; V <sub>I</sub> = 5.5V			1	10		
		$V_{CC} = 3.6V; V_I = V_{CC} \text{ or GND}$	Control pins		±0.1	±1	1	
I	Input leakage current	$V_{CC} = 3.6V; V_I = V_{CC}$	Deterring		0.1	1	μA	
		$V_{CC} = 3.6V; V_I = 0$	Data pins <sup>4</sup>		-1	-5	1	
I <sub>OFF</sub>	Output off current	$V_{CC} = 0V; V_1 \text{ or } V_0 = 0 \text{ to } 4.5V$			1	±100	μΑ	
		$V_{CC} = 3V; V_I = 0.8V$		75	150			
I <sub>HOLD</sub>	Bus Hold current A inputs <sup>7</sup>	$V_{CC} = 3V; V_1 = 2.0V$		-75	-150		μΑ	
		$V_{CC} = 0V$ to 3.6V; $V_{CC} = 3.6V$		±500				
$I_{EX}$	Current into an output in the High state when $V_O > V_{CC}$	V <sub>O</sub> = 5.5V; V <sub>CC</sub> = 3.0V			60	125	μA	
I <sub>PU/PD</sub>	Power up/down 3-State output current <sup>3</sup>	$V_{CC} \le 1.2V$ ; $V_O = 0.5V$ to $V_{CC}$ ; $V_I = GND$ OE/OE = Don't care	or $V_{CC}$ ;		1	±100	μΑ	
I <sub>OZH</sub>	3-State output High current	$V_{CC}$ = 3.6V; $V_{O}$ = 3V; $V_{I}$ = $V_{IL}$ or $V_{IH}$			1	5	μΑ	
I <sub>OZL</sub>	3-State output Low current	$V_{CC}$ = 3.6V; $V_{O}$ = 0.5V; $V_{I}$ = $V_{IL}$ or $V_{IH}$			1	-5	μΑ	
I <sub>CCH</sub>		$V_{CC}$ = 3.6V; Outputs High, V <sub>I</sub> = GND or V	/ <sub>CC,</sub> I <sub>O =</sub> 0		0.13	0.19		
I <sub>CCL</sub>	Quiescent supply current <sup>3</sup>	$V_{CC}$ = 3.6V; Outputs Low, $V_{I}$ = GND or V	<sub>CC</sub> , I <sub>O =</sub> 0		3	12	mA	
I <sub>CCZ</sub>	1	$V_{CC}$ = 3.6V; Outputs Disabled; $V_I$ = GND	or $V_{CC}$ , $I_{O} = 0^6$		0.13	0.19		
$\Delta I_{CC}$	Additional supply current per input pin <sup>2</sup>	$V_{CC} = 3V$ to 3.6V; One input at $V_{CC}$ -0.6V Other inputs at $V_{CC}$ or GND	Ι,		0.1	0.2	mA	

NOTES:

1. All typical values are at  $V_{CC} = 3.3V$  and  $T_{amb} = 25^{\circ}C$ . 2. This is the increase in supply current for each input at the specified voltage level other than  $V_{CC}$  or GND 3. This parameter is valid for any  $V_{CC}$  between 0V and 1.2V with a transition time of up to 10msec. From  $V_{CC} = 1.2V$  to  $V_{CC} = 3.3V \pm 0.3V$  a transition time of 100 $\mu$ sec is permitted. This parameter is valid for T<sub>amb</sub> = 25°C only. 4. Unused pins at V<sub>CC</sub> or GND.

5. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power. 6.  $I_{CCZ}$  is measured with outputs pulled to  $V_{CC}$  or down to GND. 7. This is the bus hold overdrive current required to force the input to the opposite logic state.

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#### **AC CHARACTERISTICS**

GND = 0V,  $t_R = t_F = 2.5$ ns,  $C_L = 50$ pF,  $R_L = 500\Omega$ ;  $T_{amb} = -40^{\circ}$ C to +85°C.

					LIMITS			
SYMBOL	PARAMETER	WAVEFORM	Vc	<sub>C</sub> = 3.3V $\pm$ 0	.3V	V <sub>CC</sub> :	= 2.7V	UNIT
			MIN	TYP <sup>1</sup>	MAX	MIN	MAX	
f <sub>MAX</sub>	Maximum clock frequency	1	125	200		125		ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay CP to Qn	1	1.7 2.2	3.2 3.5	5.1 5.2		5.8 5.5	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time to High and Low level	3 4	1.5 2.0	3.2 3.4	5.3 5.2		7.3 6.1	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time from High and Low level	3 4	1.9 2.0	4.3 3.4	6.7 5.1		7.1 5.1	ns

NOTE:

1. All typical values are at V<sub>CC</sub> = 3.3V and T<sub>amb</sub> = 25°C.

#### AC SETUP REQUIREMENTS

GND = 0V,  $t_R = t_F = 2.5ns$ ,  $C_L = 50pF$ ,  $R_L = 500\Omega$ ;  $T_{amb} = -40^{\circ}C$  to  $+85^{\circ}C$ .

SYMBOL	PARAMETER	WAVEFORM	V <sub>CC</sub> = 3.	$3V \pm 0.3V$	V <sub>CC</sub> = 2.7V	UNIT
			MIN	ТҮР	MIN	
t <sub>S</sub> (H) t <sub>S</sub> (L)	Setup time, High or Low, Dn to CP	2	2.0 2.0	0.7 0.7	2.0 2.0	ns
T <sub>H</sub> (H) T <sub>H</sub> (L)	Hold time, High or Low, Dn to CP	2	0.3 0.3	-0.5 -0.5	0 0	ns
T <sub>W</sub> (H)	CP pulse width High or Low	1	1.5 2.5	0.8 1.7	1.5 3.0	ns

## AC WAVEFORMS

 $V_{M} = 1.5V, V_{IN} = GND \text{ to } 3.0V$ 



Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency



Waveform 2. Data Setup and Hold Times



Waveform 3. 3-State Output Enable Time to High Level and Output Disable Time from High Level



Waveform 4. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

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### **TEST CIRCUIT AND WAVEFORM**



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Product specification



Product specification

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2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFERENCES			EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	1550E DATE
SOT360-1		MO-153AC				<del>-93-06-16</del> 95-02-04

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NOTES

#### Data sheet status

Data sheet status	Product status	Definition <sup>[1]</sup>
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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